

Notice of References Cited	Application/Control No. 10/002,399		Applicant(s)/Patent Under Reexamination HARDING ET AL.	
	Examiner Devesh Khare		Art Unit 1623	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,686,464 B1	02-2004	Harding et al.	536/84
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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	Examiner Devesh Khare	Art Unit 1623	Page 1 of 1

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